

IFW



XA-10277
PATENT APPLICATION

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of:

Toshihiro MIURA et al.

Appln. No.: 10/524,238

Group Art Unit: 2811

Filed: February 10, 2005

For: SEMICONDUCTOR DEVICE

* * *

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

Pursuant to 37 C.F.R. § 1.56, and without any assertion as to materiality or prior art effect, the documents listed on the attached Form PTO-1449 are hereby cited.

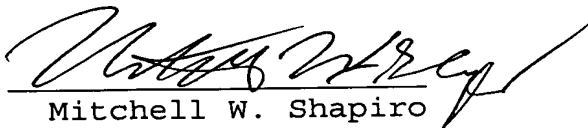
Documents AF-AK on the attached List were cited in the International Search Report (copy attached) of the parent application.

Documents AE and AF were cited in the specification, on pages 1-3, and their relevance is indicated therein.

Document AA is a counterpart of Document AF.

Respectfully submitted,

By:

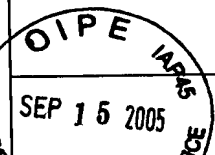

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September 15, 2005



FORM PTO-1449 INFORMATION DISCLOSURE STATEMENT LIST OF DOCUMENTS CITED BY APPLICANT		Atty. Docket No. XA-10277	Appln. No. 10/524,238
		Applicant Toshihiro MIURA et al.	
		Filing Date February 10, 2005	Group 2811

U.S. PATENT DOCUMENTS

Examiner Initial		Document Number	Date	Name	Class	Sub-class	Filing Date
	AA	6,831,360	12/14/04	Yamaura et al. (corrs. to Doc AF)	257	724	
	AB						
	AC						
	AD						

FOREIGN PATENT DOCUMENTS

Examiner Initial		Document Number	Date	Country	Class	Sub-class	Translation
	AE	2000-223623	08/11/00	Japan			Abstract
	AF	2002-208668	07/26/02	Japan			Abstract
	AG	3-227543	10/08/91	Japan			Abstract
	AH	2000-21920	01/21/00	Japan			Abstract
	AI	2001-313459	11/09/01	Japan			Abstract
	AJ	2001-237252	08/31/01	Japan			Abstract
	AK	62-291128	12/17/87	Japan			Abstract
	AL	6-349969	12/22/94	Japan			Abstract
	AM						
	AN						
	AO						
	AP						
	AQ						
	AR						

OTHER (including author, title, date, pertinent pages, etc.)

AS	
AT	
Examiner	Date Considered

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.